### Fall, 2012 Electrochemical Energy Engineering

### B

### Spectroelectrochemistry (ch. 17): in situ & ex situ

- **<u>1. UV & visible spectroscopy</u>**
- (1) Transmission experiments
- (2) Ellipsometry
- (3) Internal reflection spectroelectrochemistry: surface plasmon resonance
- (4) Second harmonic spectroscopy
- **2. Vibrational spectroscopy:**
- (1) IR spectroscopy
- (2) Raman spectroscopy
- **<u>3. Electron & ion spectroscopy</u>**
- **XPS, AES, LEED, HREELS, mass spectroscopy**
- **<u>4. Magnetic resonance methods</u>: ESR, NMR**
- **5. Quartz crystal microbalance**
- 6. X-ray methods: XAS, XRD

<u>2. Vibration spectroscopy</u>(1) Infrared spectroscopy

Energy of electromagnetic field: oscillating electric & magnetic disturbance

 $E = h\nu = h c/\lambda$ 

h; Planck constant (6.6 x  $10^{-34}$  Js) speed of light (c); 3 x  $10^8$  m/s, wavelength ( $\lambda$ ); distance between the neighboring peaks of wave,  $1 \text{ Å} = 0.1 \text{ nm} = 10^{-10} \text{ m}$ frequency (v, Hz = 1 s<sup>-1</sup>); number of times per second  $\lambda v = c$ wavenumber (cm<sup>-1</sup>, reciprocal cm), v-bar = v/c = 1/ $\lambda$ cf) 1 eV ~ 8066 cm<sup>-1</sup>

Wavelength  $(\lambda, nm) = 1240/band gap energy (eV)$ 

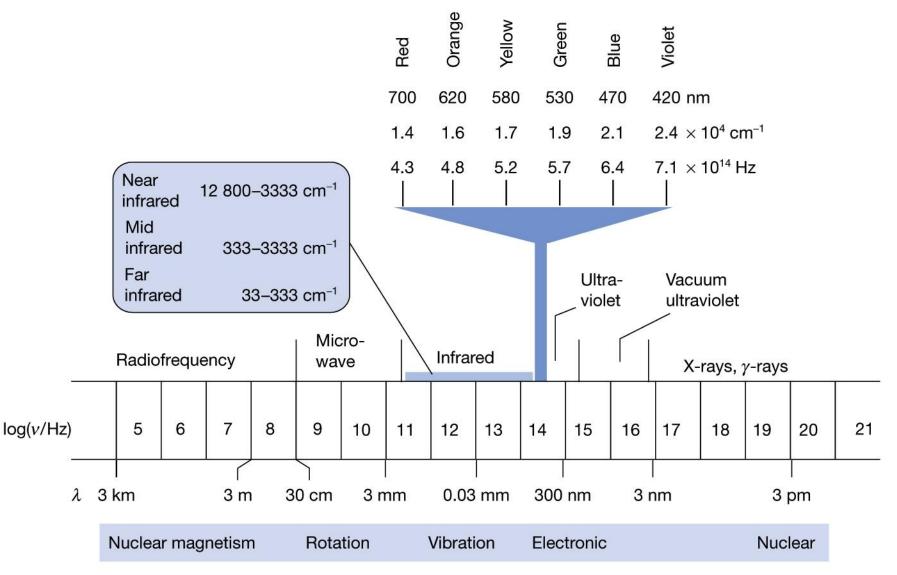
### Widely used IR spectroscopy: mid-IR (670~4000 cm<sup>-1</sup>( $2.5 \sim 14.9 \mu m$ ))

Spectral Regions	Measurement Type	Kind of Analysis	Applicable Samples
Near-IR	Diffuse reflectance	Quantitative	Solid or liquid commercial materials
	Absorption	Quantitative	Gaseous mixtures
Mid-IR	Absorption	Qualitative	Pure solid, liquid, or gases
		Quantitative	Complex liquid, solid, or gaseous mixtures
		Chromatographic	Complex liquid, solid, or gaseous mixtures
	Reflectance	Qualitative	Pure solids or liquids
	Emission	Quantitative	Atmospheric samples
Far-IR	Absorption	Qualitative	Pure inorganic or organometallic species

TABLE 17-1 Major Applications of IR Spectrometry

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#### **Electromagnetic spectrum**

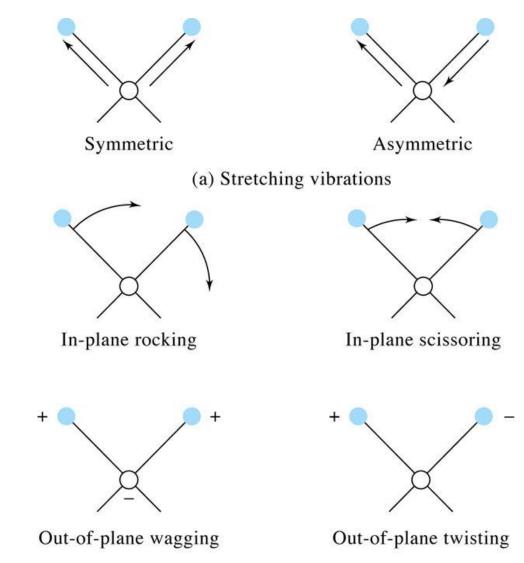


IR radiation ~ energy differences for vibrational & rotational states

For absorption of IR radiation: dipole moment change during vibration

Dipole moment is determined by the magnitude of the charge difference and the distance between two centers of charge e.g) H-Cl (o) O-O (x)

Types of vibration: Stretching & bending



(b) Bending vibrations

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#### Harmonic oscillator

$$F = -ky$$
 Hooke's law

k: force constant -: opposite direction for the force - A Potential energy:  $E = \frac{1}{2} ky^2$ т 0 Potential energy E +A0 0 +A-ADisplacement y (a)

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### Vibrational frequency

$$\mathbf{F} = \mathbf{ma} = \mathbf{m}(\mathbf{d}^2\mathbf{y}/\mathbf{dt}^2) = -\mathbf{ky}$$

 $y = Acos(2\pi vt)$ 

Frequency of mechanical oscillator

 $v = (1/2\pi)\sqrt{(k/m)}$ 

Reduced mass:  $\mu = m_1 m_2 / (m_1 + m_2)$ 

 $v = (1/2\pi)\sqrt{(k/\mu)}$ 

Quantum treatment of vibration:

 $E = (v + \frac{1}{2})(h/2\pi)\sqrt{(k/\mu)}$ 

h: Planck's constant, v: vibrational quantum number

$$\Delta E = hv = (h/2\pi)\sqrt{(k/\mu)}$$
Ground state at v = 0:  

$$E_{0} = \frac{1}{2} hv$$

$$I^{st} \text{ excited state (v = 1)}$$

$$E_{1} = 3/2 hv$$
Required radiation energy:  

$$(3/2 - \frac{1}{2})hv = hv$$

$$= (h/2\pi)\sqrt{(k/\mu)}$$
(b) 1. Harmonic oscillator

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2. Anharmonic motion

Wavenumber (cm<sup>-1</sup>): v-bar =  $(1/2\pi c)\sqrt{(k/\mu)}$ = 5.3 x 10<sup>-12</sup> $\sqrt{(k/\mu)}$ 

#### Selection rules

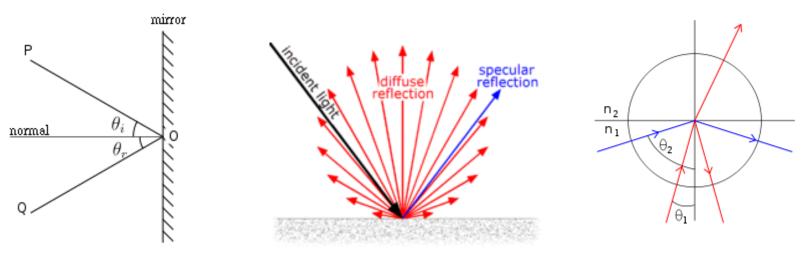
Gross selection rule for IR: change of dipole moment e.g., symmetric stretch of  $CO_2$ : no dipole moment change  $\rightarrow$  IR inactive antisymmetric stretch, bending modes  $\rightarrow$  IR active

Specific selection rule  $\Delta v_q = \pm 1$  in harmonic approximation

Molecules can be identified from characteristic frequencies and intensities

IR reflection spectrometry

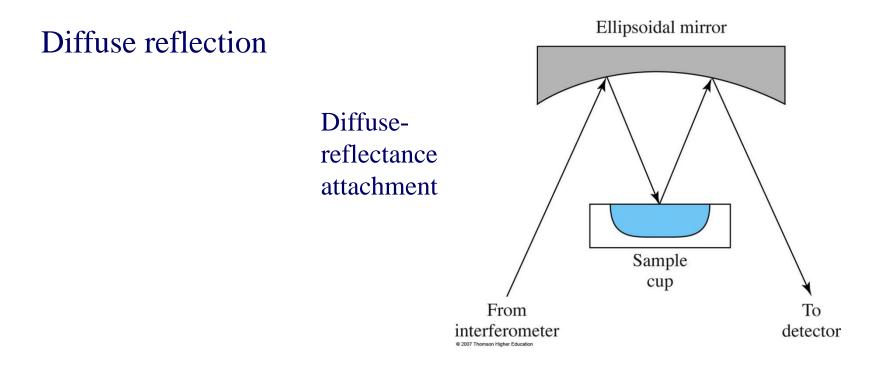
Four types: Specular reflection: smooth surface Diffuse reflection Internal reflection Attenuated total reflection (ATR)



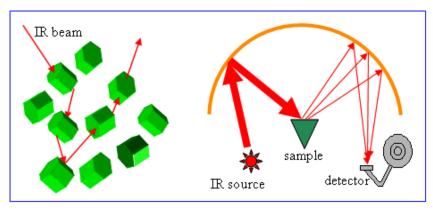
Specular reflection

Diffuse reflection

Internal reflection (blue line)



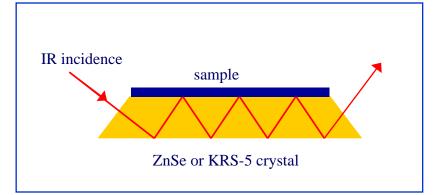
Diffuse Reflectance Infrared Fourier Transform Spectroscopy (DRIFT)



Powder sample

Attenuated total reflectance (ATR) is a sampling technique used in conjunction with infrared spectroscopy which enables samples to be examined directly in the solid, liquid or gas state without further preparation

ATR uses a property of total internal reflection resulting in an evanescent wave. A beam of infrared light is passed through the ATR crystal in such a way that it reflects at least once off the internal surface in contact

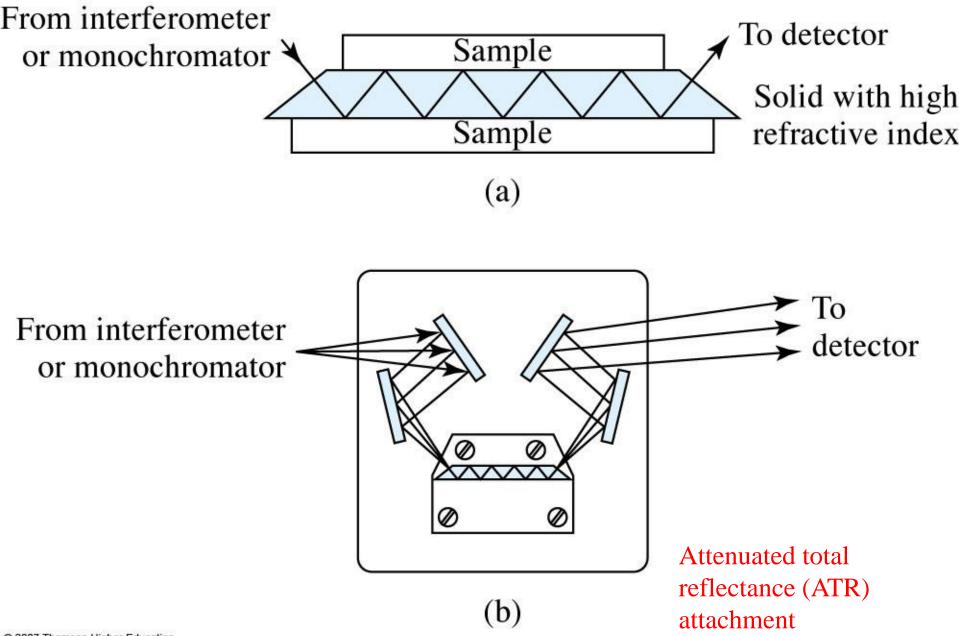


Attenuated Total Reflectance Spectroscopy (ATR)

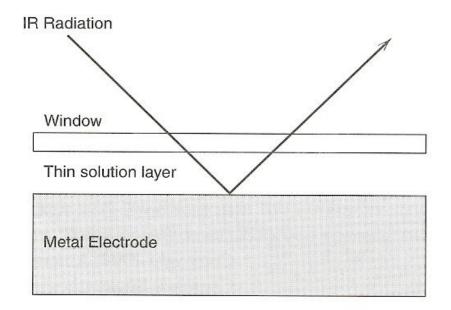
with the sample. This reflection forms the evanescent wave which extends into the sample. The penetration depth into the sample is typically between 0.5 and 2 micrometres, with the exact value being determined by the wavelength of light, the angle of incidence and the indices of refraction for the ATR crystal and the medium being probed. The number of reflections may be varied by varying the angle of incidence. The beam is then collected by a detector as it exits the crystal. Most modern infrared spectrometers can be converted to characterise samples via ATR by mounting the ATR accessory in the spectrometer's sample compartment. The accessibility of ATR-FTIR has led to substantial use by the scientific community.

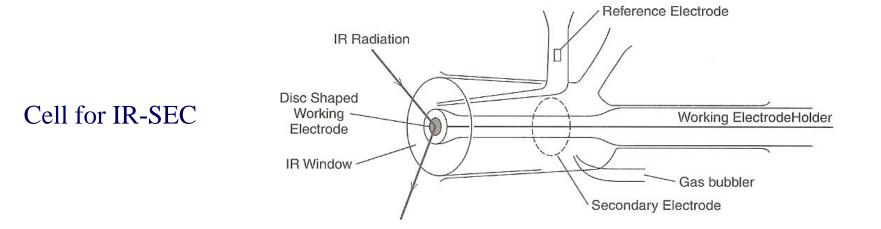
This evanescent effect only works if the crystal is made of an optical material with a higher refractive index than the sample being studied. Otherwise light is lost to the sample. In the case of a liquid sample, pouring a shallow amount over the surface of the crystal is sufficient. In the case of a solid sample, it is pressed into direct contact with the crystal. Because the evanescent wave into the solid sample is improved with a more intimate contact, solid samples are usually firmly clamped against the ATR crystal, so that trapped air is not the medium through which the evanescent wave travels, as that would distort the results.

Typical materials for ATR crystals include germanium, KRS-5 and zinc selenide, while silicon is ideal for use in the Far-IR region of the electromagnetic spectrum. The excellent mechanical properties of diamond make it an ideal material for ATR, particularly when studying very hard solids, but its much higher cost means it is less widely used. The shape of the crystal depends on the type of spectrometer and nature of the sample. With dispersive spectrometers, the crystal is a rectangular slab with chamfered edges, seen in cross-section in the illustrations. With FTIR cylindrical crystals are used with liquid samples. (출처: 위키백과)



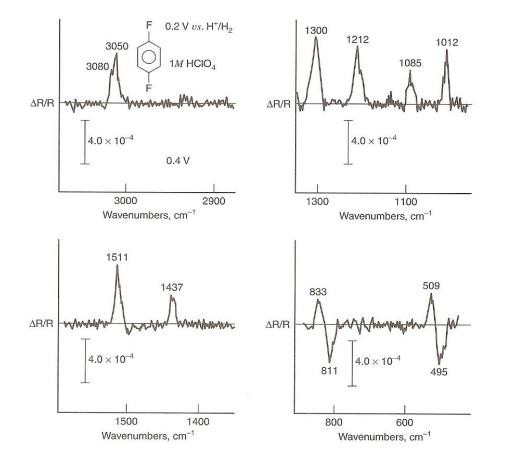
#### Infrared spectroelectrochemistry (IR-SEC)





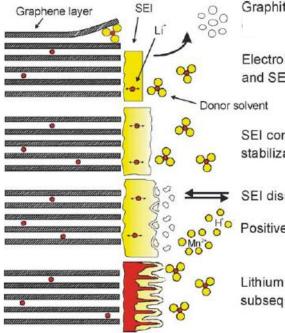
#### **SEIRA** (surface enhanced IR absorption)

IR to study adsorbed species (reactants, intermediates, products)  $\rightarrow$  orientation & potential dependence of the adsorbed species



P-difluorobenzene in 1 M HClO<sub>4</sub> at a Pt electrode

# Why in-situ FT-IR spectroscopy ?



Graphite exfoliation, cracking

Electrolyte decomposition and SEI formation

SEI conversion, stabilization and growth

SEI dissolution, precipitation

Positive / Negative interactions

Lithium plating and subsequent corrosion

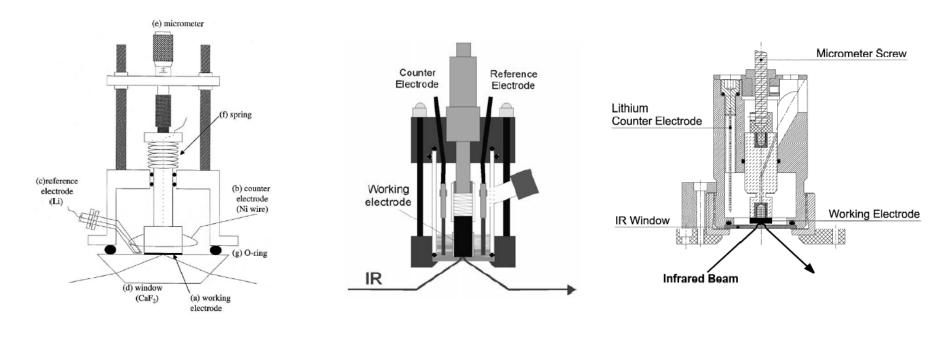
#### Changes at the anode/electrolyte interface

- Electrolyte decomposition occurs at the electrode/electrolyte interfaces
- Formation of SEI (solid electrolyte interface)
- Mechanisms of the electrolyte decomposition process have been the subject of many investigation

- > Necessity of In-situ FT- IR spectroscopy
- 1. Investigation of electrolyte at the electrode surface without contamination
- 2.imformation about electrolyte decomposition
- 3. formation of SEI



# in-situ FT-IR Cell



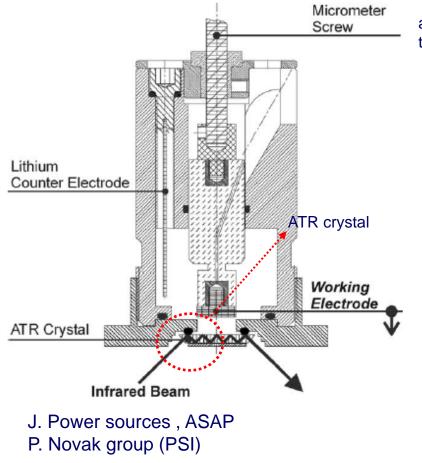
Electrochim. Acta 47, 2001, 433 Kanamura group

Anal. Bioanal. Chem. 379, 2004, 266 Moller group J. Power sources 90, 2002, 52 P. Novak group (PSI)

Disadvantage: weak sensitivity (single beam)



# Cell model of In-situ FT-IR



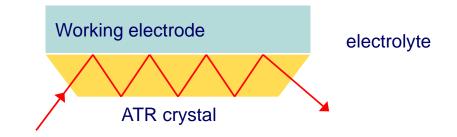
The decisive innovation is the use of an ATR crystal as the optical window. Five reflections can he increasing, thus, the sensitivity significantly. (P.Novak group)

#### Selection of ATR crystal

Materials	Freguency Rage(cm <sup>-1</sup> )	Index of Refraction	Characteristics
KRS-5	16,500-250	2.4	wide frequency Range
ZnSe	20,000-650	2.4	water insoluble

Sealing problem

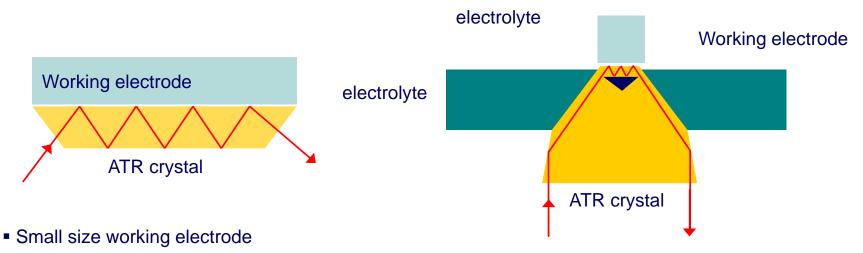
Diffusion problem



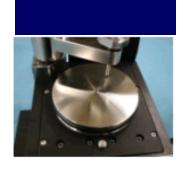
QVAB

# Cell model of In-situ FT-IR

Diffusion problem



- Three –reflection hexagon ATR crystal
- Beam alignment

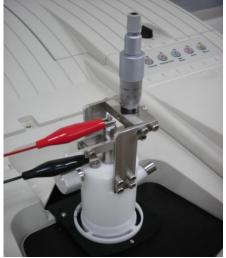


MIRacle<sup>TM</sup> ATR PIKE technologies /USA



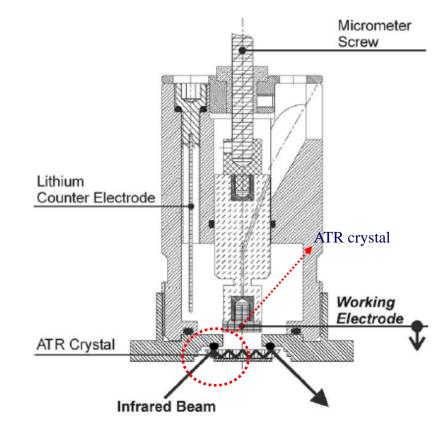
# In situ FT-IR (SNU)





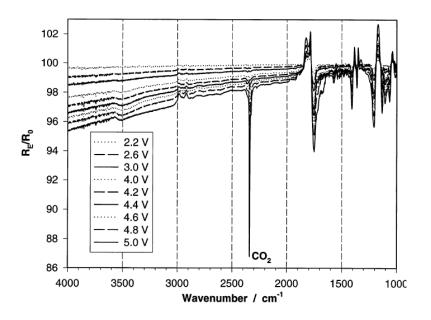
In situ FT IR cell

- Nicolet 5700 (thermo electron co.)
- ATR, DRIFT, in situ analysis
- 7,800~350cm-1 ( DLaTGS w/KBr Detector)

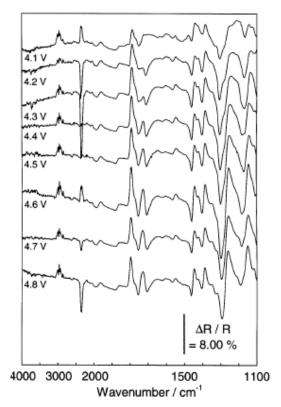


# in-situ FT-IR spectroscopy

■ 활용의 예



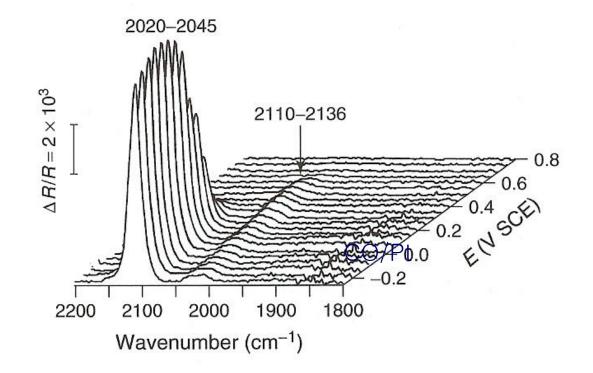
In situ FTIR spectra on a polished nickel electrode Electrolyte solution, 1 M  $\text{LiClO}_4$  in PC (Electrochim. acta 45, 2000, 3589), Novak group



FTIR spectra for the electrochemical oxidation of 1.0 mol dm<sup>-3</sup> LiPF6/propylene carbonate on the  $LiCoO_2$  film electrode

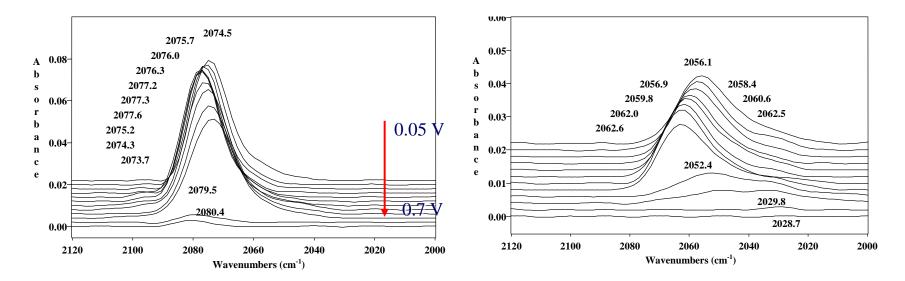


### ✤ In situ FT-IR





CO/Pt



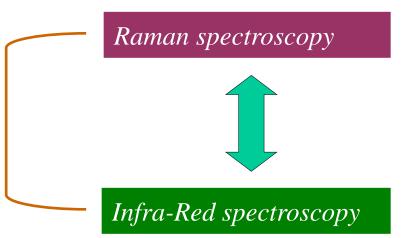
Pure Pt, 50 % CO

PtRu(1:1), 50 % CO

Change of bonding energy of CO-Pt

<u>2. Vibration spectroscopy</u>(2) Raman spectroscopy

Virational spectroscopy



# Comparison: IR vs. Raman

### Infra-Red spectroscopy

- Absorption
- IR source
- Change of dipole moment, charge distribution

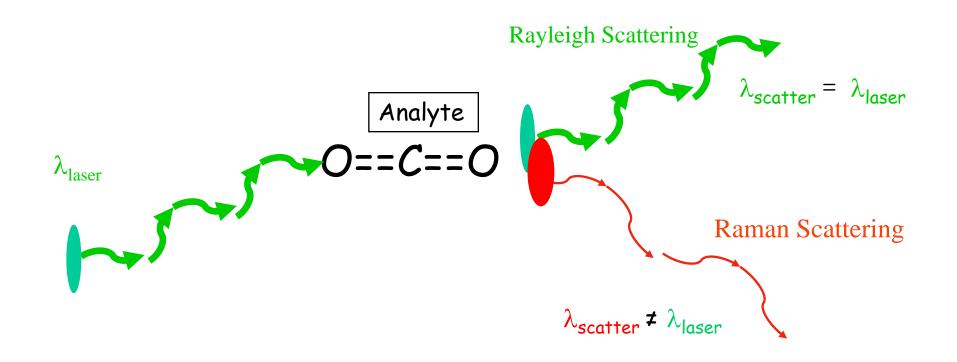
#### Raman spectroscopy

- Scattering
- Visible or NIR source.
- Change of polarizability

#### In case of homonuclear molecule, IR inactive, Raman active

O C O

# What is Raman effect ?



A Light Scattering Process: A photon (Laser source at only one wavelength) bounces off a molecule and loses a small amount of energy equal to the vibrational energy of the molecule.

## Scattering of radiation (산란)

The transmission of radiation in matter  $\rightarrow$  momentary retention of the radiation energy by atoms, ions, and molecules  $\rightarrow$  reemission of the radiation in all directions as the particles return to their original state: scattering

Rayleigh scattering: scattering smaller than the wavelength of the radiation . 파장에 비하여 작은 미립자에 의한 현상으로 산광의 세기가 파장의 4제곱에 반비례, 단파장의 빛일수 록 강하게 산란.

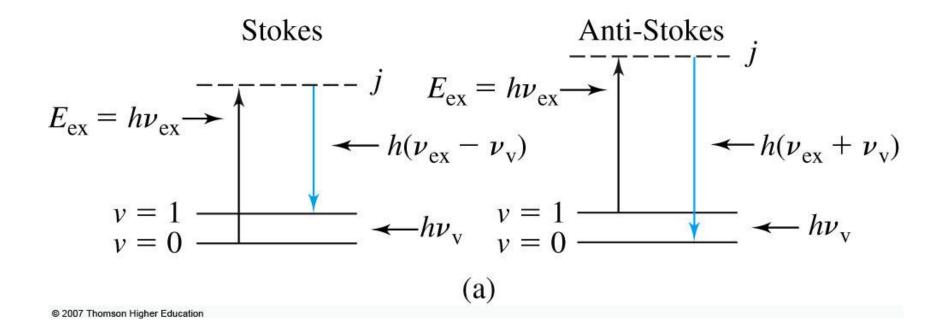
e.g., blue color of the sky: greater scattering of the shorter wavelength of visible spectrum 아침/저녁놀: 단파장 산란, 장파장 투과하기 때문에 붉게 보임

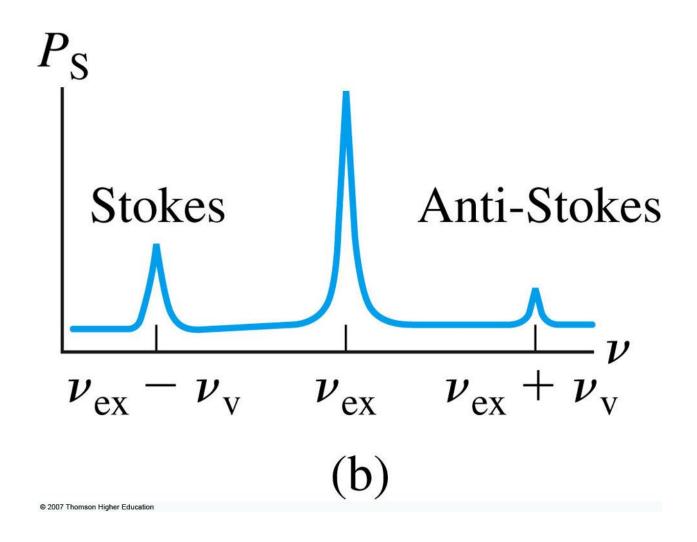
Scattering by large molecules: With large particle, scattering can be different in different directions (Mie scattering, 빛의 파장과 거의 같은 크기의 입자들에 의해 일어나는 산란 현상. 대기오염 물질이 많을 때 대기가 회색을 띄는 예) → used to determine the size and shape of large molecules and colloidal particles

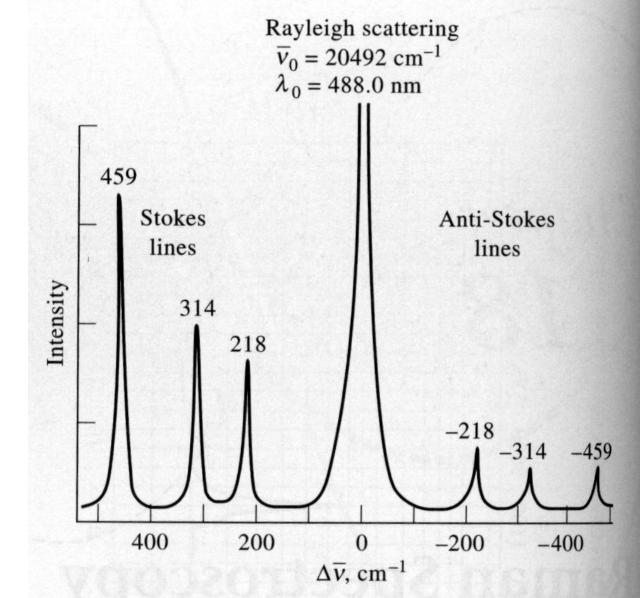
Raman scattering: from vibrational energy level transitions that occur in the molecules as a consequence of the polarization process. Raman spectroscopy에 이용. (대부분 산란은 입 사광선의 파장과 같지만 라만효과는 입사광선과 파장이 다름

Monochromatic beam of energy  $hv_{ex} \rightarrow excitation$  to a virtual state  $j \rightarrow scattering$ 

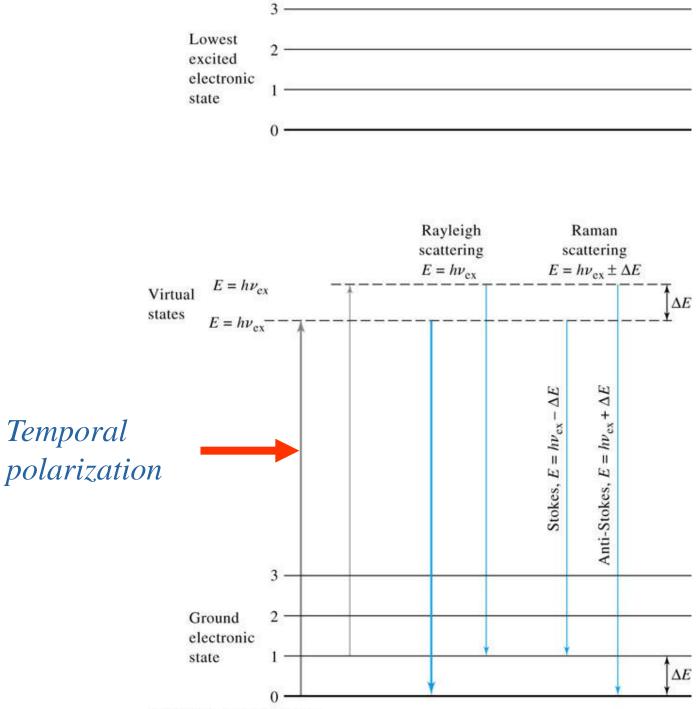
Frequency shift of inelastic scattering = vibrational frequency







 $CCl_4$ Excited by laser (488 nm (= 20492 cm<sup>-1</sup>)



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# **Scattering Model**

 $E = E_0 \cos(2\pi v_{ex} t) \qquad \qquad E : Laser \ electric \ field$ 

 $m = \alpha E = \alpha E_0 \cos(2\pi v_{ex} t)$ 

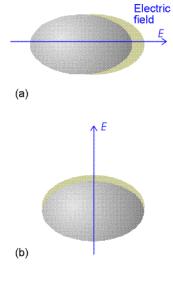


*α* : Polarizability

$$\alpha = \alpha_0 + (r - r_{eq}) \left( \frac{\partial \alpha}{\partial r} \right) \qquad r - r_{eq} = r_m \cos(2\pi v_v t)$$

$$\alpha = \alpha_0 + \left(\frac{\partial \alpha}{\partial r}\right) r_m \cos(2\pi v_v t)$$

$$m = \alpha_0 E_0 \cos(2\pi v_{ex}t) + E_0 r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos(2\pi v_v t) \cos(2\pi v_{ex}t)$$



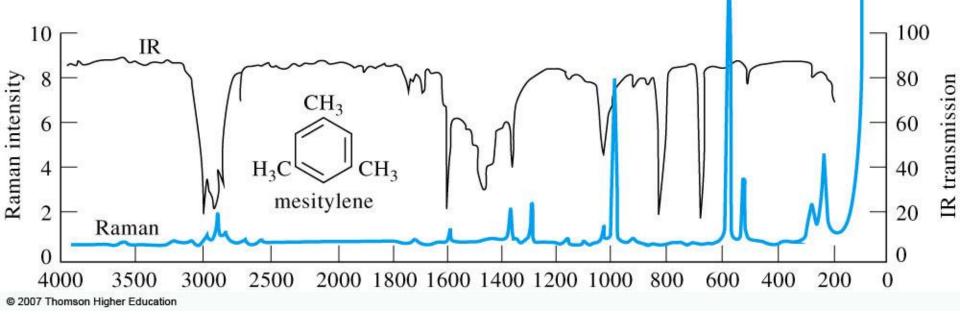
### Induced dipole moment (m)

$$m = \alpha_0 E_0 \cos(2\pi v_{ex}t) + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} - v_v)t\right] + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Stokes line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Anti-stokes line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_{ex} + v_v)t\right] \\ \underset{\text{Rayleigh line}}{\text{Rayleigh line}} + \frac{E_0}{2} r_m \left(\frac{\partial \alpha}{\partial r}\right) \cos\left[2\pi (v_$$

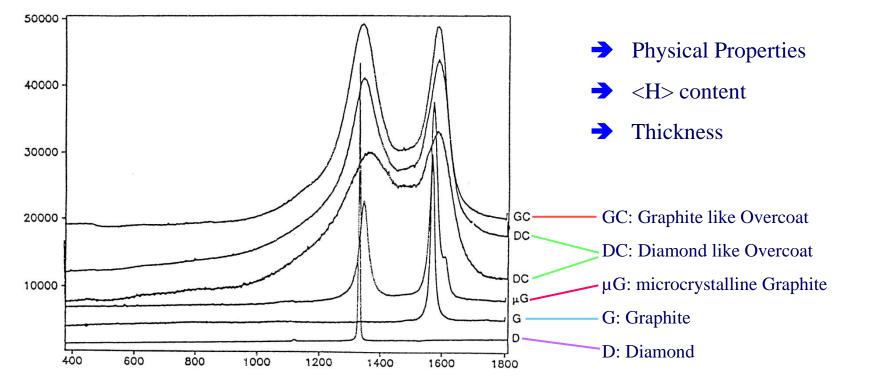
$$rac{\partial lpha}{\partial r} 
eq 0 \,\,$$
 : Raman에 active하기 위한 조건

#### IR vs. Raman

### Similar, different intensities Different in some peaks: IR active or inactive, Raman active or inactive e.g., symmetric mode of $CO_2$ : IR inactive, Raman active



#### Raman Spectra of different modifications of carbon



#### JY Horiba Raman Division

# What is Raman Spectroscopy offering?

- Qualitative results
  - ✓ Identification
  - ✓ Nature of functional groups
  - $\checkmark$  Structure: crystalline or amorphous phases
  - ✓ Specific physical properties
- Quantitative results (calibration is necessary)
- Benefits of Raman Spectroscopy
  - □ No need for sample preparation.
    - Water inactive.
  - □ Non-destructive, non-invasive technique.
    - Laser energy is low so the sample remains intact.

### What can Raman Spectra tell us ?

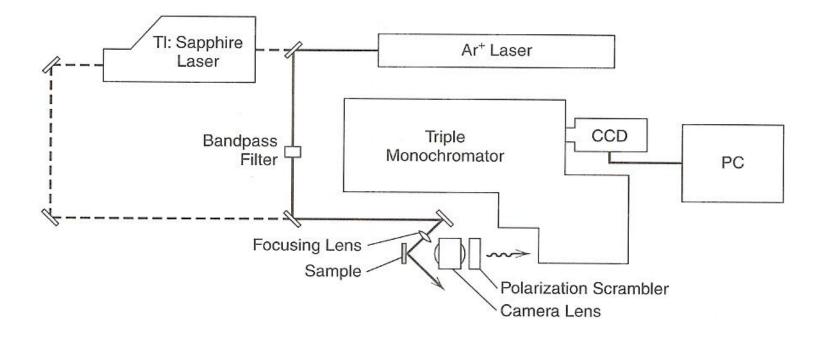
• Vibrational frequencies are characteristic of chemical bonds or groups of bonds in a specific molecule: normal modes

- A Raman spectrum provides a fingerprint of the set of bonds present in the material
- Vibrational frequencies are sensitive to details of the local environment of a molecule, such as crystal phase, local strain, and degree of crystallinity.
- Relative intensities within a spectrum can quantify the orientation of the bond w.r.t. the incoming laser polarization
- Raman spectroscopy can be complementary to IR

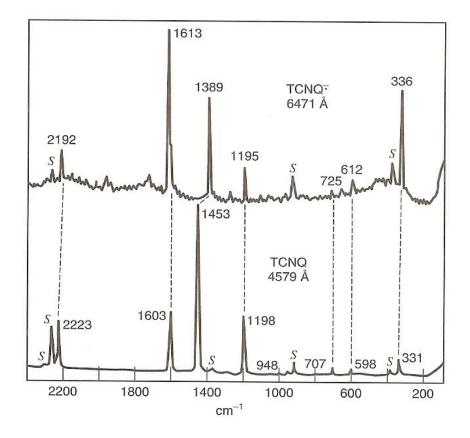
Raman spectroscopy: molecular vibrational information complementing IR spec. Raman in electrochemical system: signal enhancement

- Resonance Raman spectroscopy (RRS)
- Surface enhanced Raman spec. (SERS): molecules adsorbed on certain surfaces

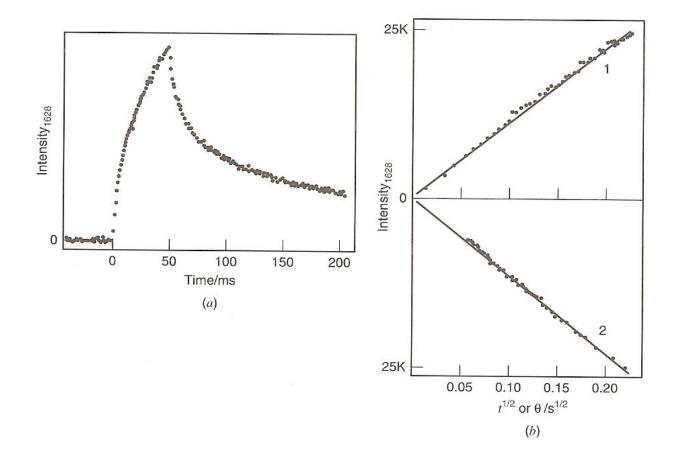
(Ag or Au)



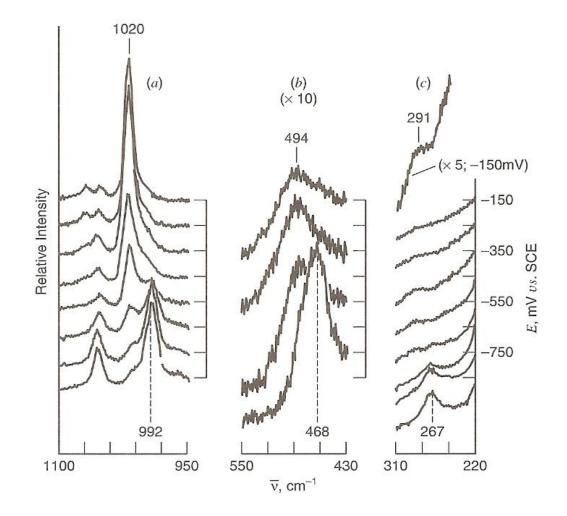
#### RRS of TCNQ & electrochemically generated TCNQ<sup>-</sup>



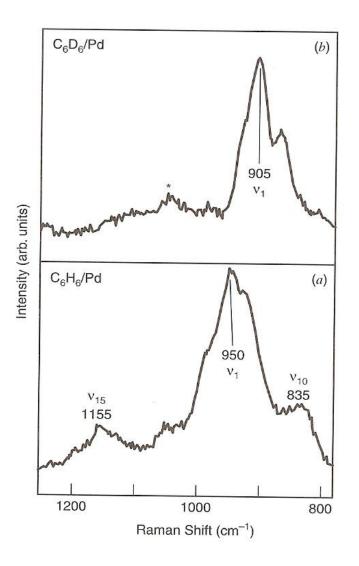
#### **Transients in Raman intensity**



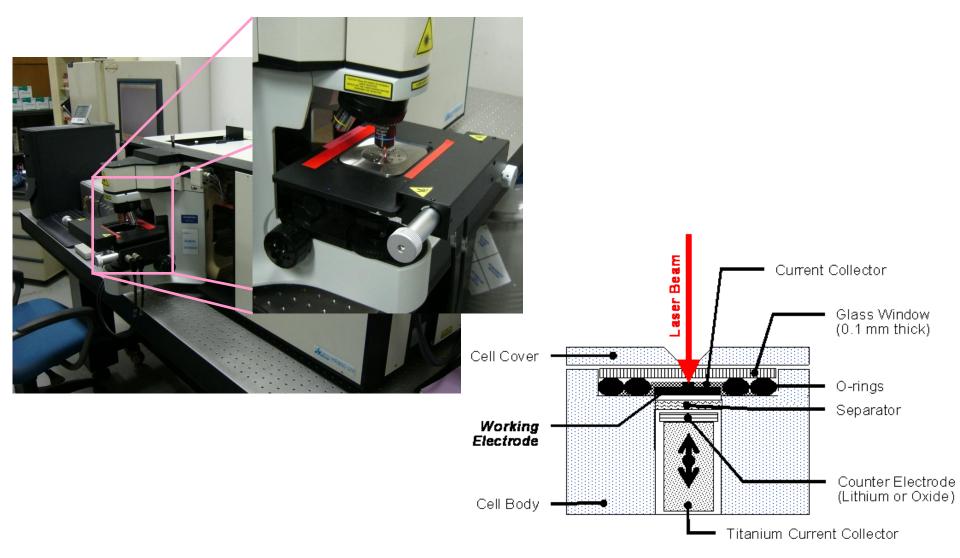
#### SERS for Os compound on Ag electrode as ftn of potential



#### SER spectra for benzene on Pd



## In-situ Raman Spectroscopy (SNU)



# Specifications of HR LabRam



Covering spectral range from 200-1600 nm



Laser : Ar ion laser : 514.5 nm (green), 50 mW. He/Ne laser : 632.8 nm (red), 17 mW.



Grating : 1800 gr/mm, 600 gr/mm



Visible objetive : 10X, 50X, 100X, 50X LWD



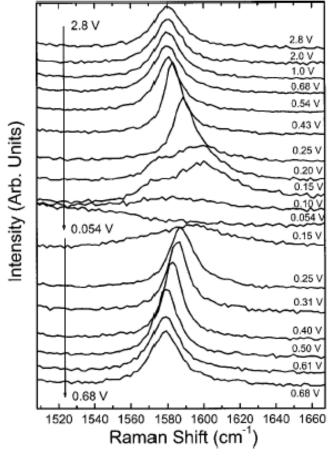
CCD detector : a multichannel  $LN_2$  cooled (-133 °C) 1024 × 256 pixels



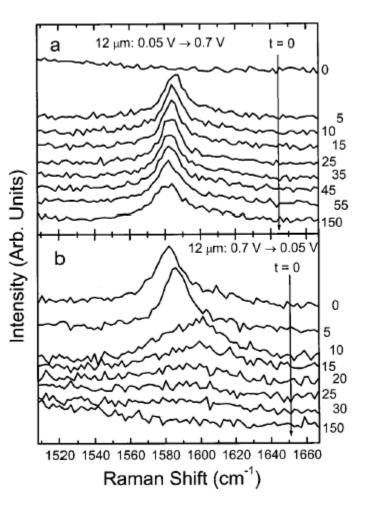
Center for Materials of Advanced Batteries

# Structural Changes according to Li+ intercalation

✤ Li<sup>+</sup> intercalation



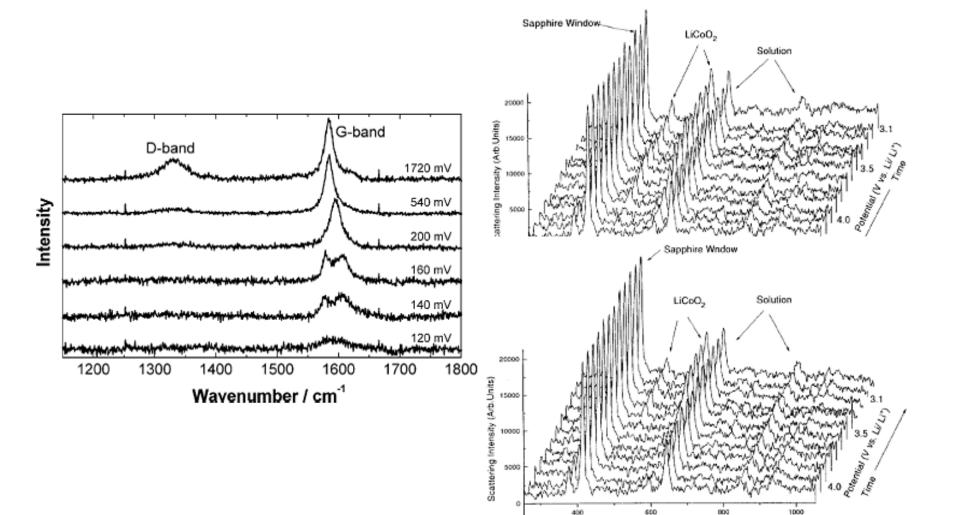
Scherson (2002)



# CVAB

#### Center for Materials of Advanced Batteries

## Structural Changes according to Li+ intercalation

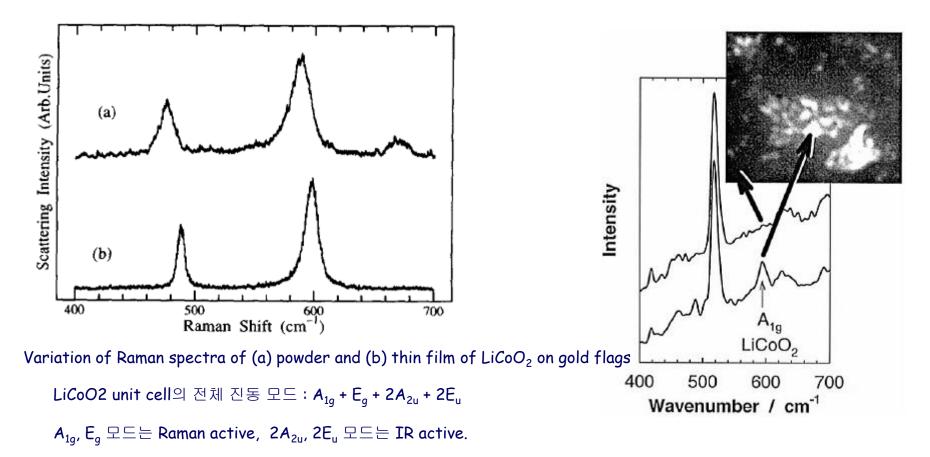


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Raman Shift (cm<sup>-1</sup>)





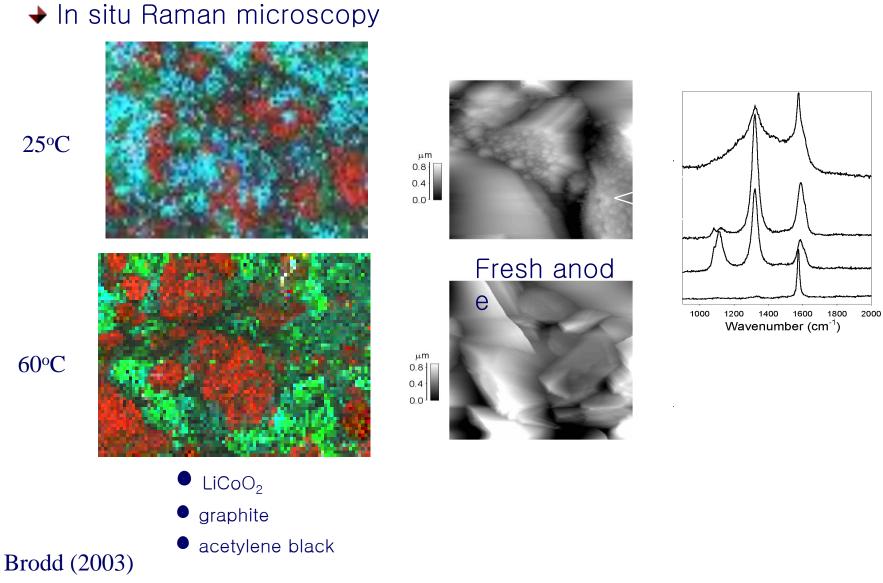


485cm<sup>-1</sup> 와 597 cm<sup>-1</sup> 에서의 라만 라인은 각각 A<sub>1q</sub>, E<sub>q</sub> 모드에 해당.

Peak의 shift와 width 차이 -> Film의 결정성이 뛰어나기 때문에

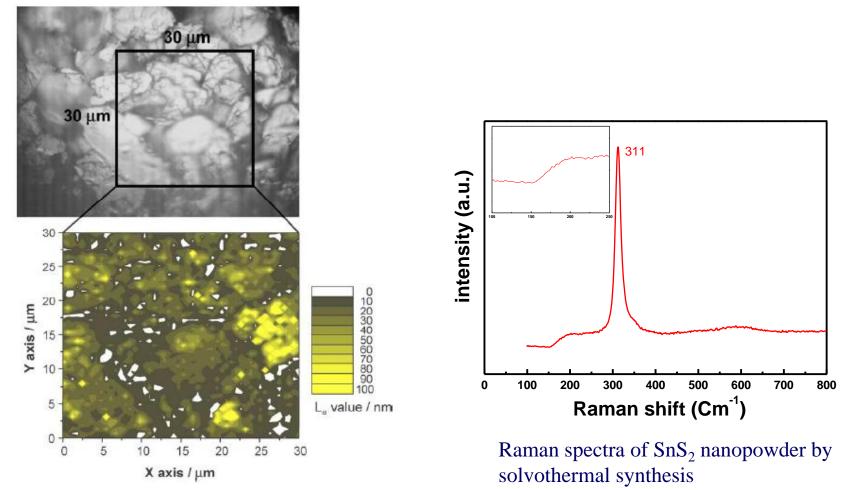


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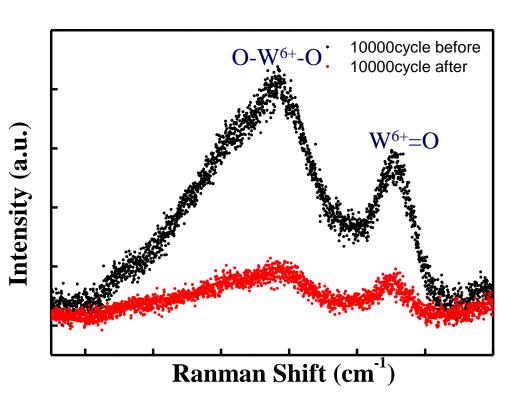




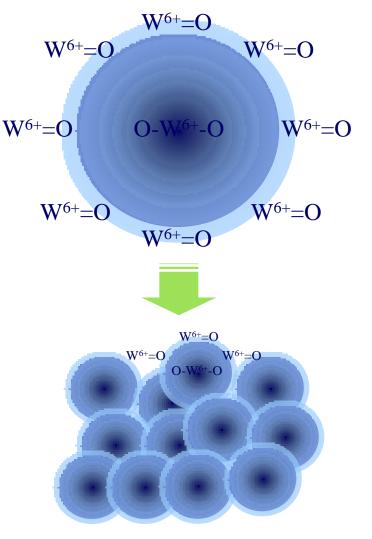
2005 CMAB

Raman mapping of graphite surface: a graphite sample (top) and spatial distribution plot of the  $L_a$  values

## In situ Raman - WO<sub>3</sub>

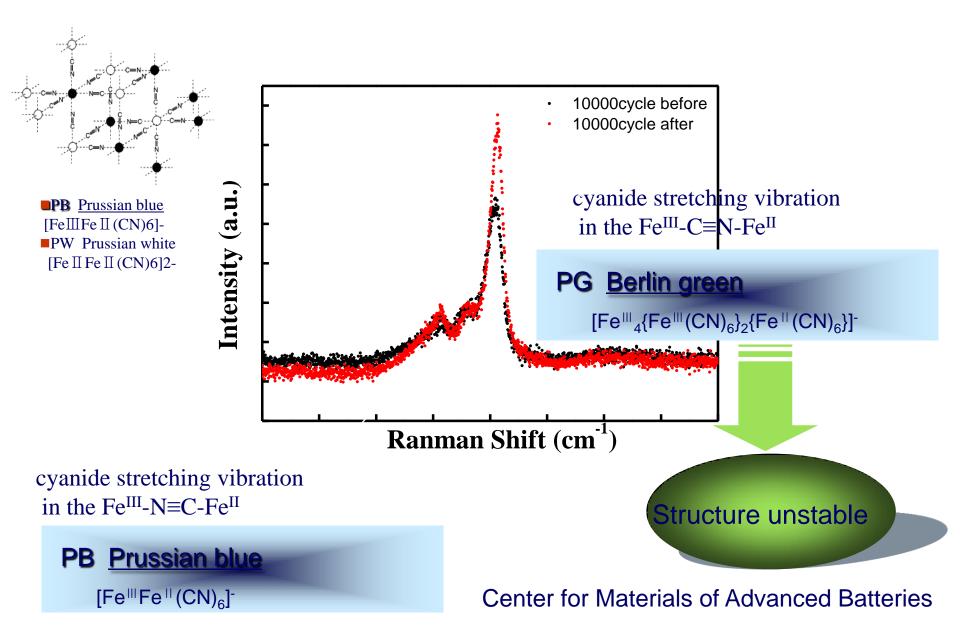


•The W<sup>6+</sup>=O/O-W<sup>6+</sup>-O ratio → increase
•The grain size → decrease

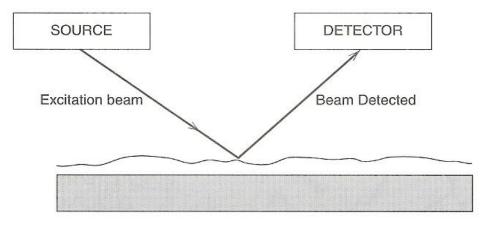


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## Raman data - PB



## **Electron and ion spectrometry** Ultra high vacuum (UHV)



#### Excitation

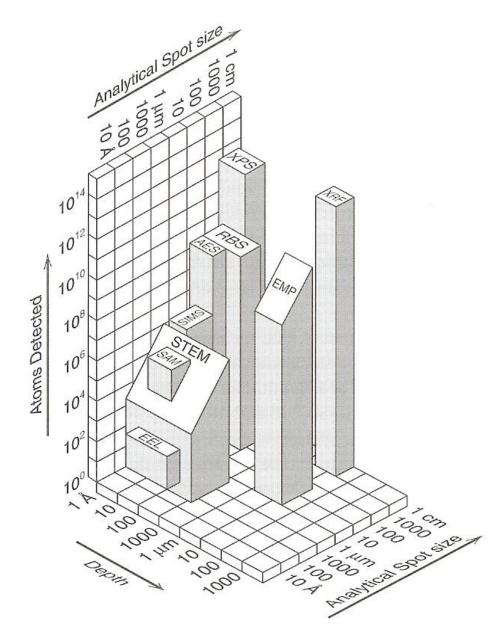
#### Detection

X-ray photoelectron spectroscopy (XPS)
VV photoelectron spectroscopy (UPS)
Auger electron spectroscopy (AES)
Low-energy electron diffraction (LEED)
High resolution e<sup>-</sup> E loss spec. (HREELS)
Ele
Rutherford backscattering (RBS)
H4
Secondary ion mass spec. (SIMS)
Laser desorption mass spec. (LDMS)

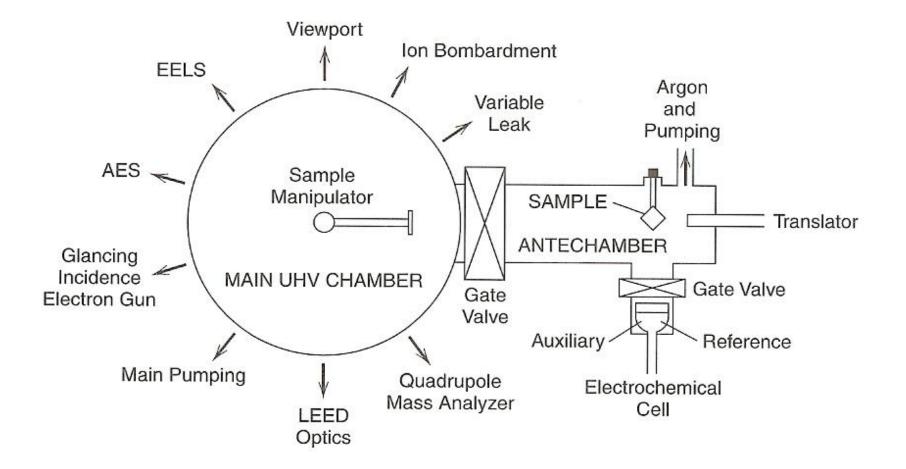
Photons(X-ray) Photons (UV) Electrons Electrons Electrons H+ or He+ Ions Photons

Electrons Electrons Electrons Electrons Electrons H+ or He+ Ions Ions

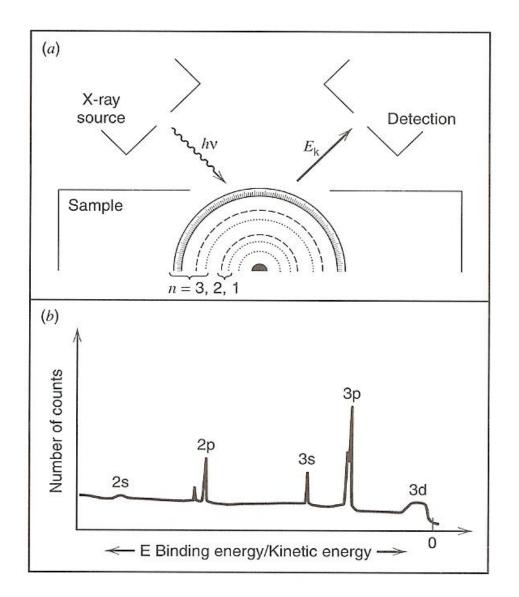
#### Detection limits, sampling depth, spot size (spatial resolution)



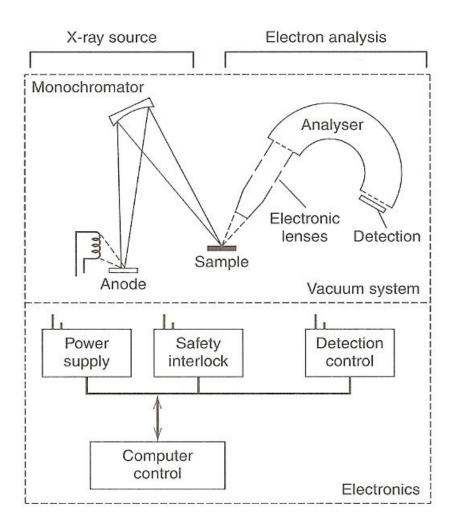
#### UHV-electrochemistry



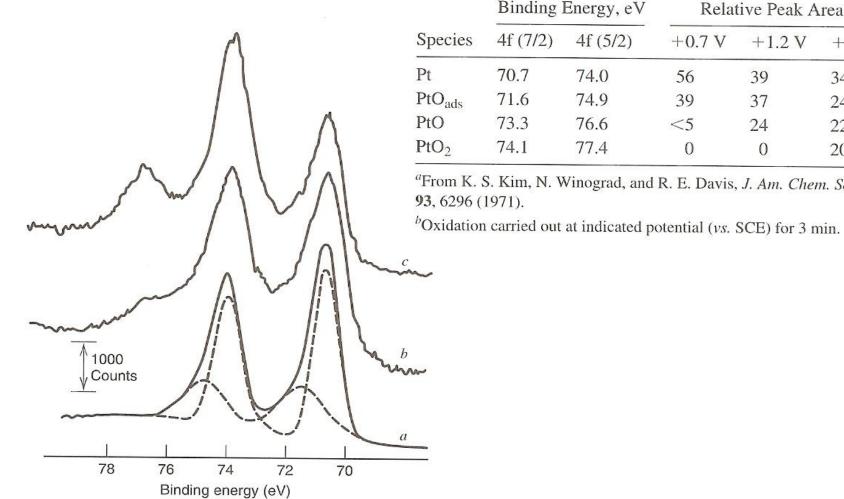
#### X-ray photoelectron spectroscopy (XPS, or ESCA)



#### Schematic diagram of XPS



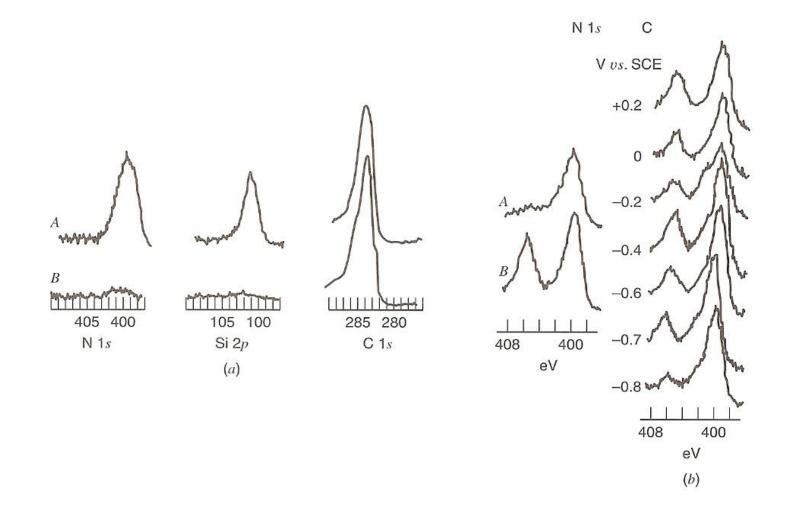
#### XPS for Pt 4f levels:



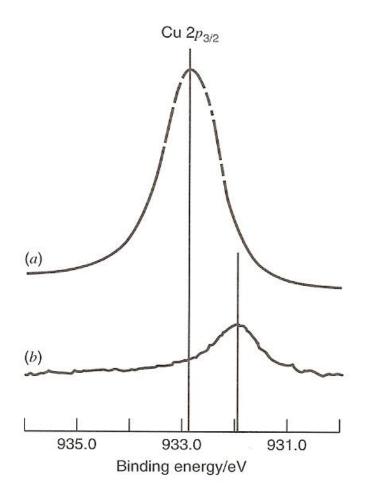
Relative Peak Areas <sup>b</sup>		Binding Energy, eV		
+1.2 V +2.2 V	+0.7 V	4f (5/2)	4f (7/2)	Species
39 34	56	74.0	70.7	Pt
37 24	39	74.9	71.6	PtO <sub>ads</sub>
24 22	<5	76.6	73.3	PtO
0 20	0	77.4	74.1	PtO <sub>2</sub>
24 22	<5		Marco China Ma	PtO

<sup>a</sup>From K. S. Kim, N. Winograd, and R. E. Davis, J. Am. Chem. Soc.,

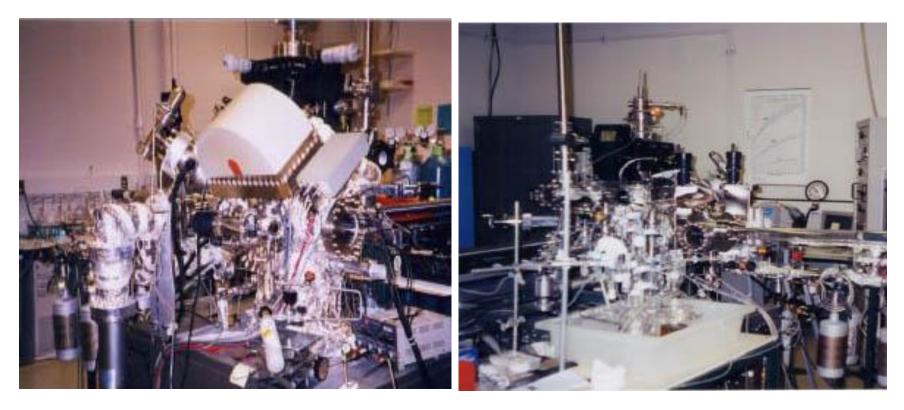
#### XPS for gassy carbon electrodes



#### XPS for copper electrodeposition (a) Bulk Cu (b) Cu UPD



#### **Electrochemical X-ray Photoelectron Spectroscopy**



Univ. of Illinois

## Electrochemical XPS (SNU)

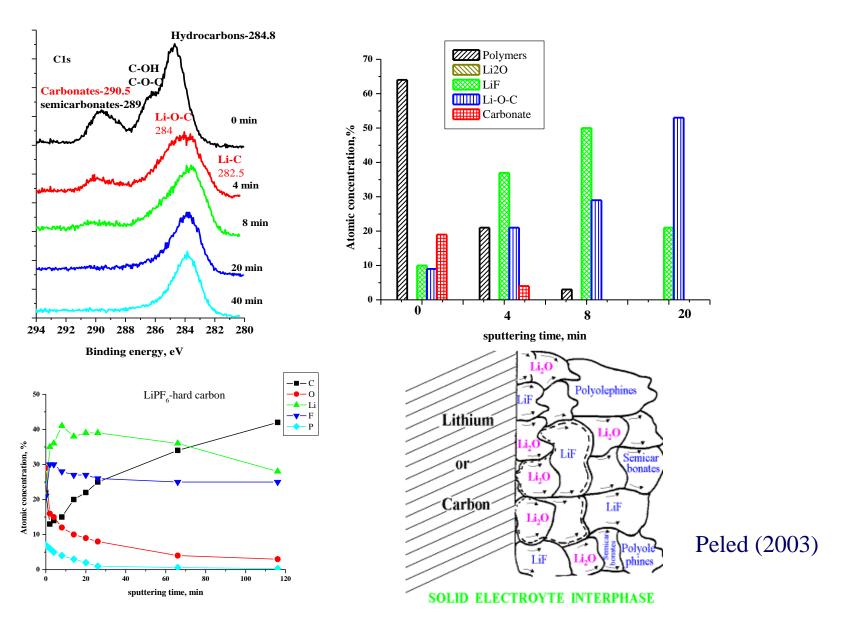


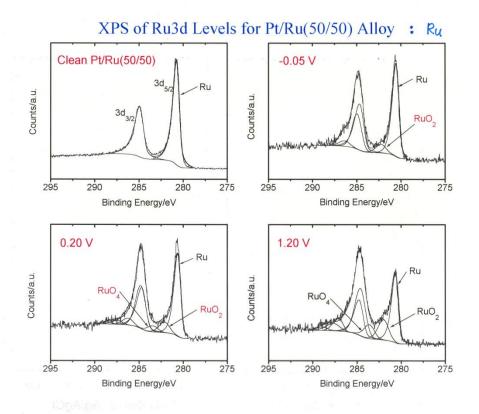
UHV-XPS Glove Box



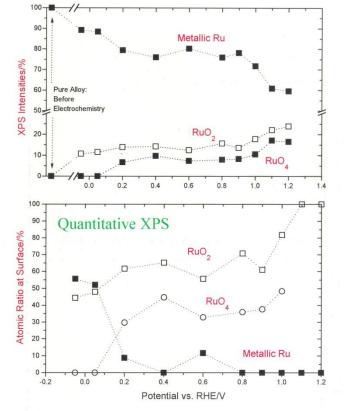
## **Ex-situ** Analysis without Contamination

## Electrochemical XPS





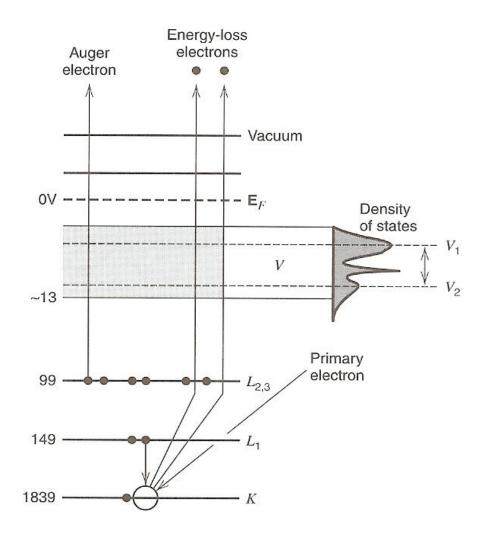
Relative Amount of Ru Species



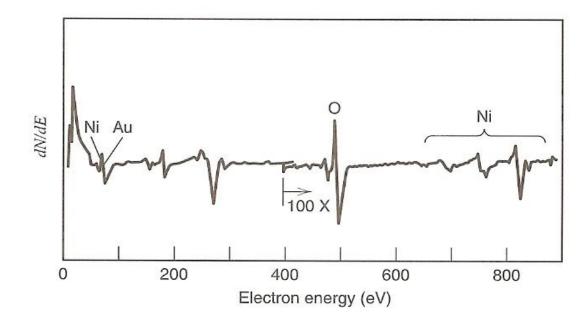
PtRu during Electrochemistry

#### Center for Materials of Advanced Batteries

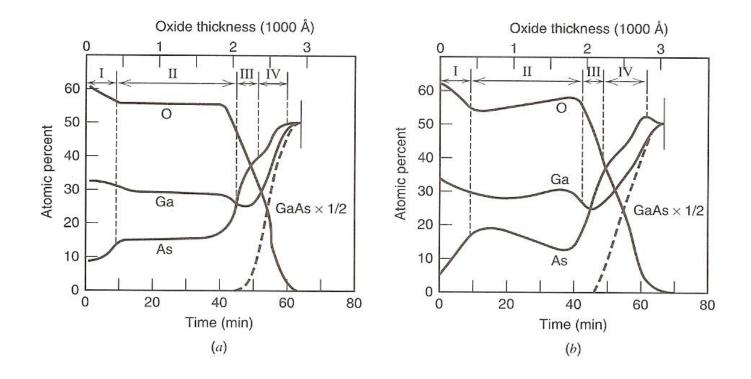
#### Auger electron spectroscopy



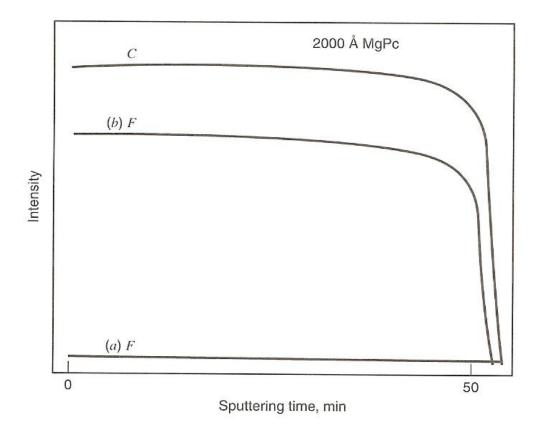
#### Ni oxide on Au



#### AES Depth profiles for GaAs



## AES depth profiles for MgPc

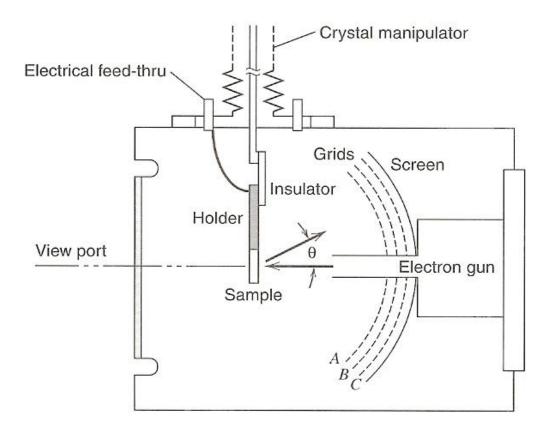


#### *Electrochemical* Auger Electron Spectroscopy

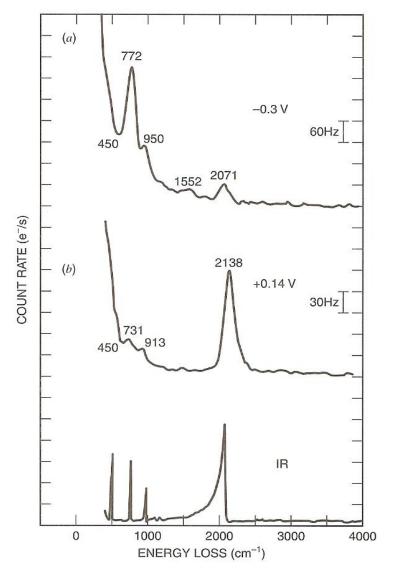


## Univ. of Illinois

#### Low-energy electron diffraction



#### High resolution electron energy loss spectroscopy

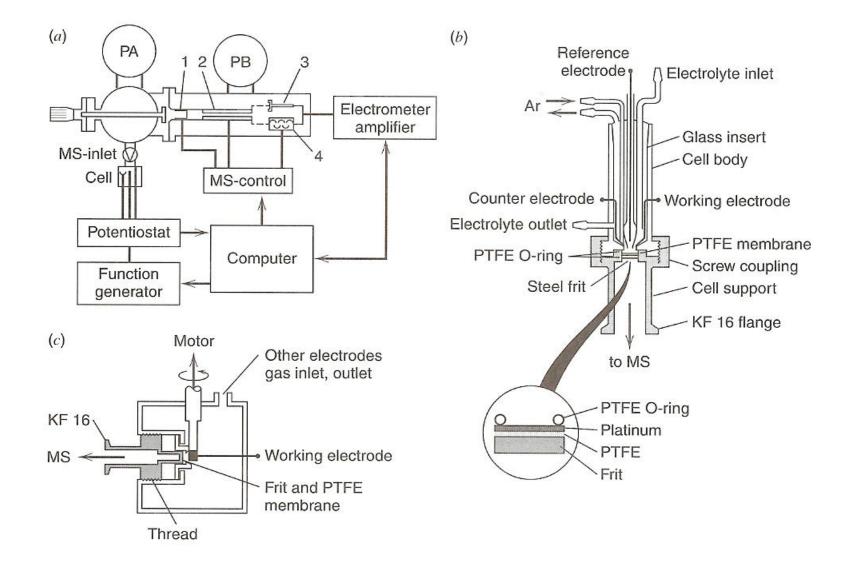


```
SCN<sup>-</sup> on Ag(111)
```

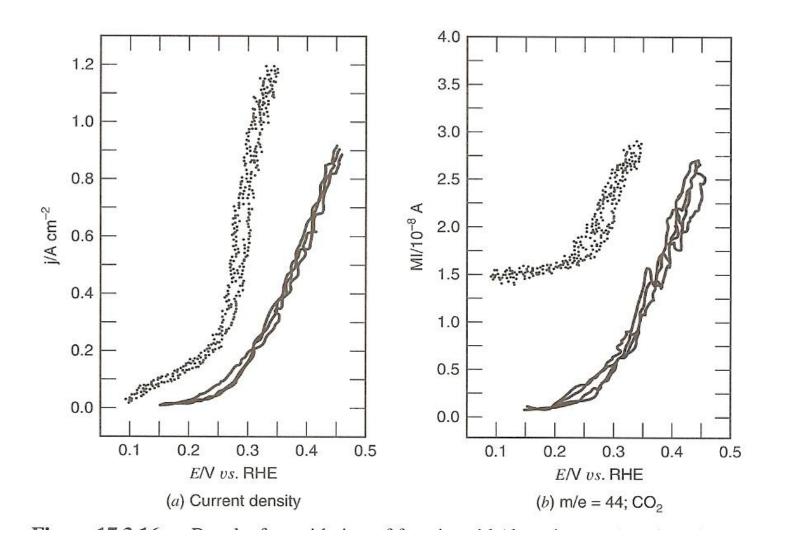
```
(a) -0.3 V
(b) +0.14 V
```

#### **Mass spectrometry**

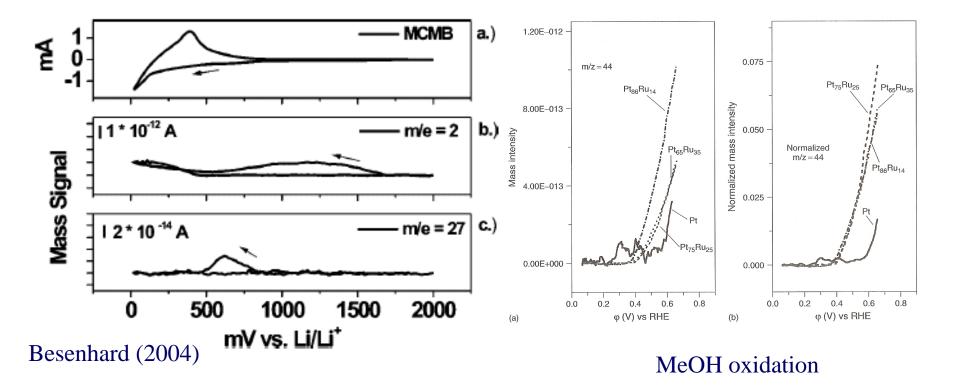
#### Differential electrochemical mass spectrometry (DEMS)



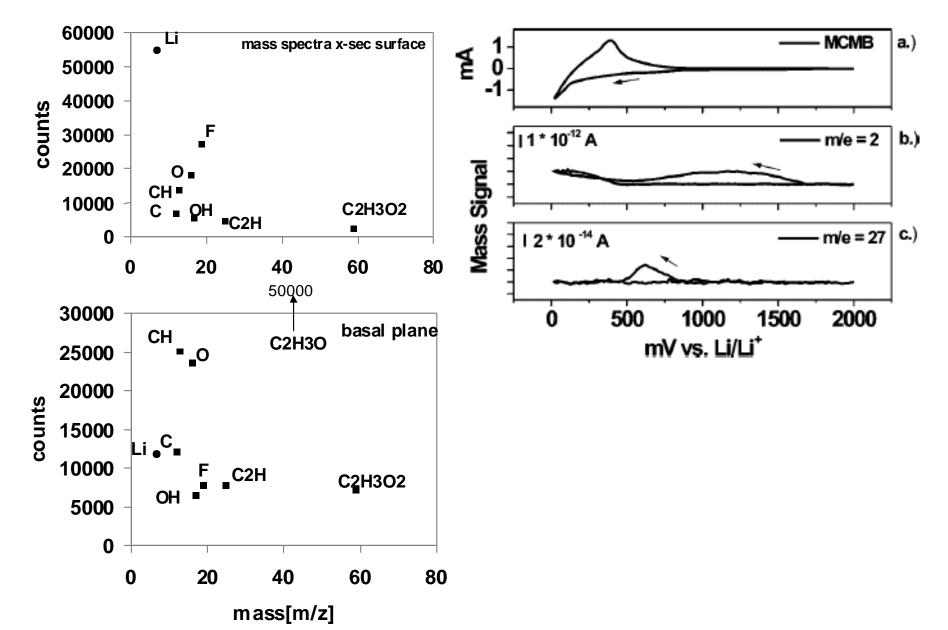
#### DEMS: fuel cell catalysts for methanol(solid) & formic acid(dotted) oxidation



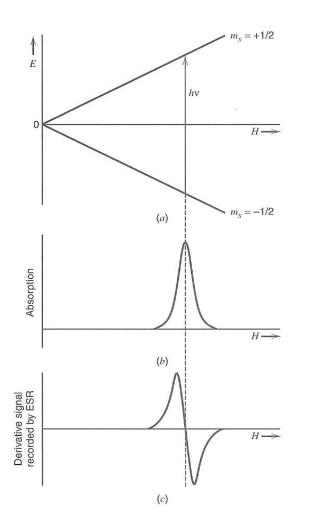
#### ✤ In situ DEMS (differential electrochemical mass spectroscopy)



#### in-situ DEMS (differential electrochemical mass spectroscopy)

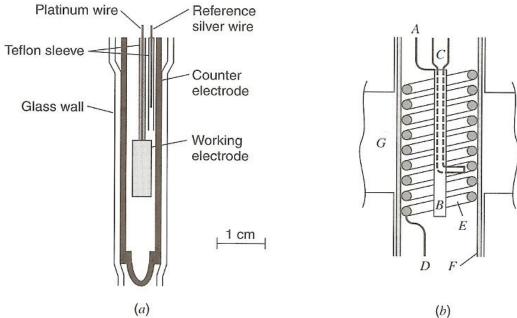


## **Magnetic resonance methods Electron spin resonance & NMR**



<sup>&</sup>lt;sup>4</sup>First edition, pp. 615–621.

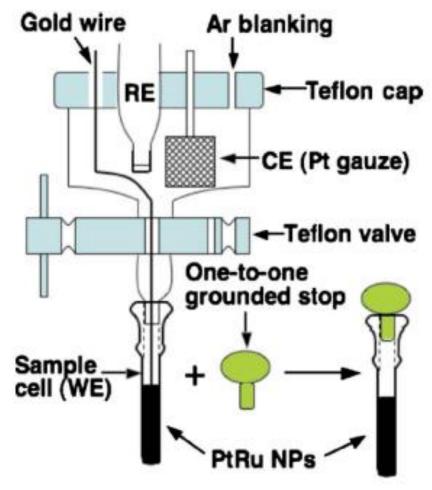
### **Electrochemical ESR**



(b)

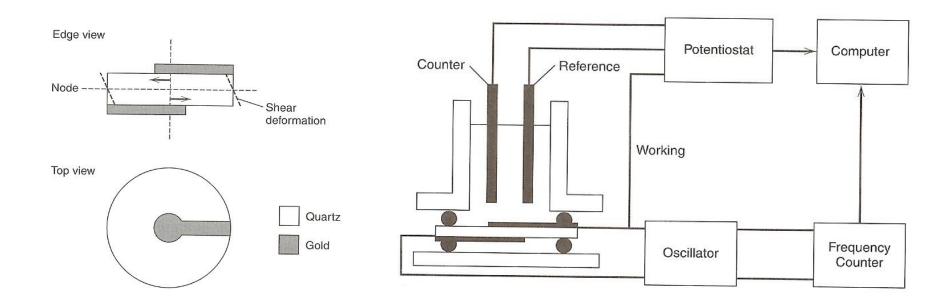
## in-situ NMR



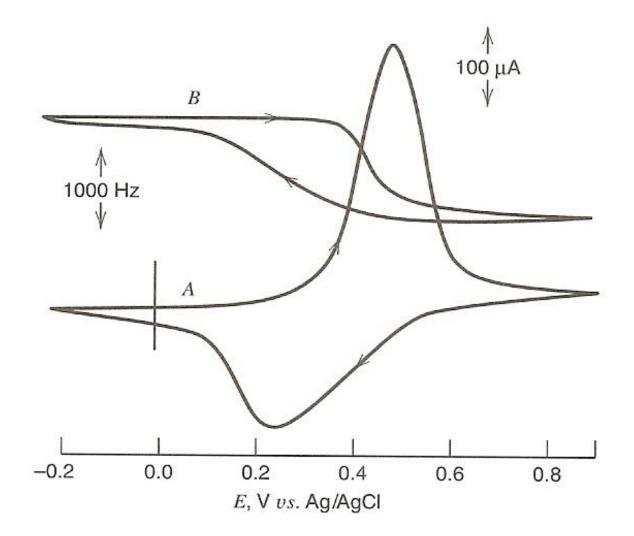


## (with Prof. YuYe Tong (Georgetown University))

### Quartz crystal microbalance



## QCM: PVF on Au



## X-ray methods Synchrotron

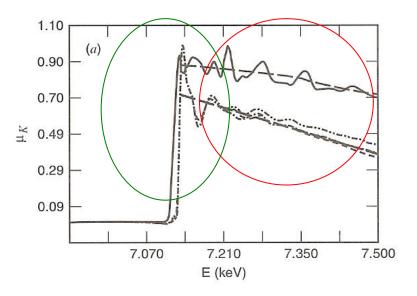
### X-ray absorption spectroscopy

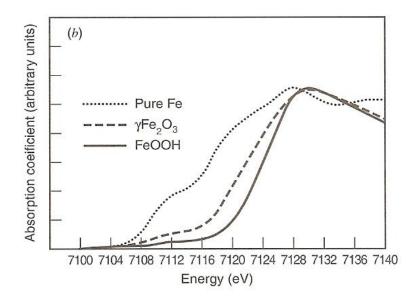
Absorption edge (energy that is just needed to eject a particular core electron, e.g., 1s e<sup>-</sup> (K edge),  $2p_{3/2}$  e<sup>-</sup> (L<sub>3</sub> edge)

Fe & Fe oxides K-edge: 7.112 keV

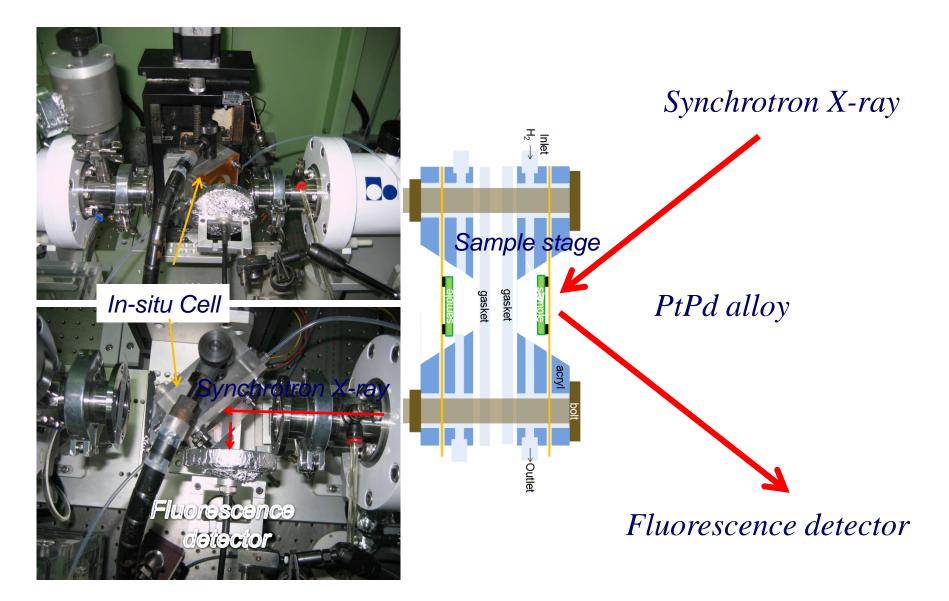
Within 10-40 eV: X-ray absorption near-edge structure (XANES) (or near-edge absorption fine structure (NEXAFS))  $\rightarrow$  oxidation state & ligand envirionment

About 50 keV: extended X-ray absorption Fine structure (**EXAFS**)  $\rightarrow$  distance & arrangement of atoms

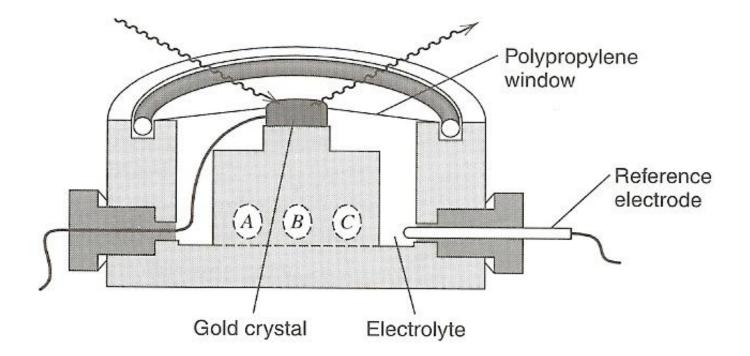




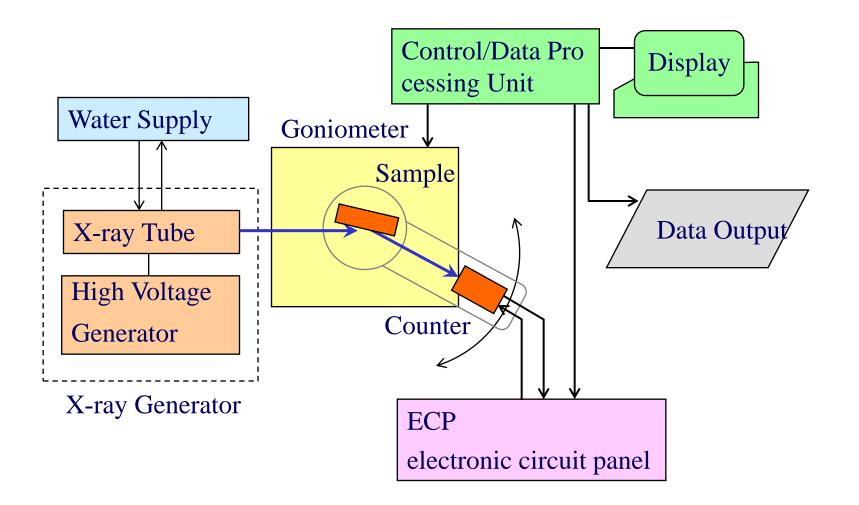
## In-situ XANES (X-ray Absorption Near-Edge Structure)



### **X-ray diffraction techniques**

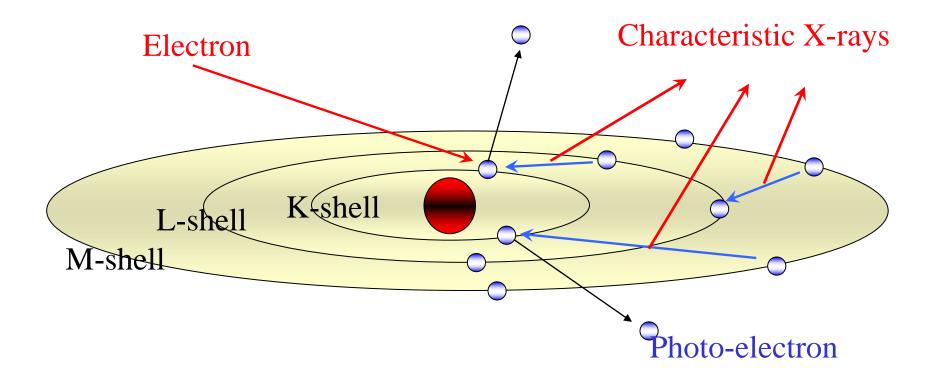


## **X-Ray Diffractometer**



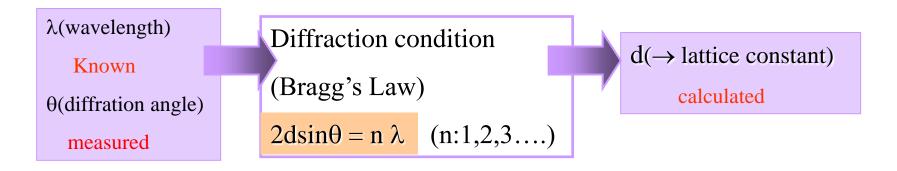


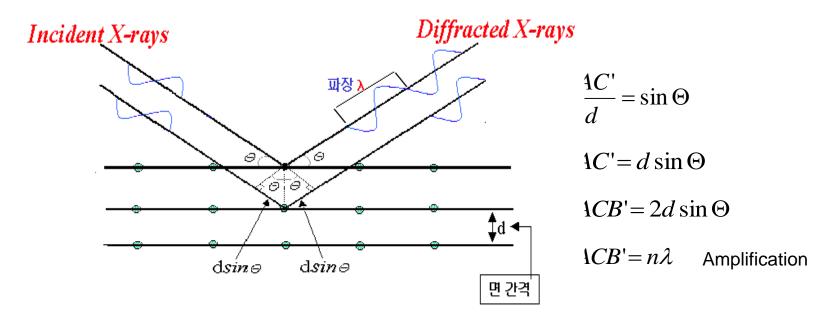
## **Characteristic X-ray**





# X-ray diffraction (Bragg's Law)







# Rigaku - D/MAX 2500/PC (SNU)



18kW X-ray generator
 -high frequency type
 -rotating anode(Cu etc.)

- High power generator -rapid, highly accurate
  - -enhance S/N ratio
  - -trace analysis
  - -analysis of weakly
  - diffracting material
- Goniometer
   -vertical type

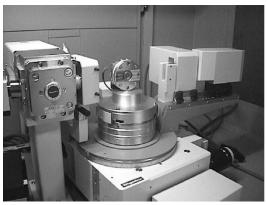
Large enclosure type – Two goniometer



# in situ XRD (SNU)



- ■powder X-Ray Diffractometer, D/MAX 2500/PC
- •powder, thin film, in situ analysis



In situ cell



